

10/561125

<b>FORM PTO-1449 (SUBSTITUTE)</b>  <b>U.S. DEPARTMENT OF COMMERCE</b> <b>PATENT AND TRADEMARK OFFICE</b>  <b>INFORMATION DISCLOSURE</b> <b>STATEMENT BY APPLICANT</b> <b>(37 CFR 1.97(b)(1))</b>	<b>Attorney Docket No.:</b> <b>S3-04P03410</b>  <b>Applicant</b> <b>Klaus Heimerl, et al.</b>  <b>Filing Date</b> <b>December 15, 2005</b>	<b>Applicant No.</b> <b>Concurrently herewith</b>  <b>Group Art Unit</b>
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EXAMINE R INITIALS		PATENT NO.	DATE	PATENTEE	<del>CLASS</del>	<del>SUB CLASS</del>	FILING DATE
/TN/	A	6,196,580 B1	03/2001	Eberle, et al.			
	B	2002/0033755 A1	03/2002	Ishizaki, et al.			
	C	2002/0180596 A1	12/2002	Mattes, et al.			
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		DOCUMENT NO.	DATE	COUNTRY	<del>CLASS</del>	<del>SUB CLASS</del>	TRANSL. YES   NO
/TN/	J	WO 03/082639 A1	10/2003	WIPO			
	K	DE 197 18 803 C1	10/1998	Germany			
	L	DE 197 36 840 A1	02/1999	Germany			
	M	DE 198 51 981 A1	05/2000	Germany			
	N	DE 100 45 698 A1	05/2001	Germany			
	O	DE 100 03 992 A1	08/2001	Germany			
/TN/	P	DE 100 23 588 A1	11/2001	Germany			

<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>	
<b>EXAMINER</b> /Tan Q. Nguyen/	<b>DATE CONSIDERED</b> 09/17/2008
<b>EXAMINER:</b> Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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STATEMENT BY APPLICANT  
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Group Art Unit

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	A						
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	G						
	H						
	I						

## FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	<del>CLASS</del>	SUB CLASS	TRANSL. YES   NO
/TN/	J	DE 100 30 465 A1	01/2002	Germany			
↓	K	DE 100 39 755 A1	02/2002	Germany			
↓	L	DE 100 16 142 A1	04/2002	Germany			
↓	M	DE 101 45 698 A1	05/2002	Germany			
↓	N	DE 101 13 720 A1	09/2002	Germany			
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